

Supporting Information

Low-temperature and template-free fabrication of cobalt oxide acicular nanotube arrays and their application for supercapacitors

Chung-Wei Kung^a, Yu-Heng Cheng^a, Chuan-Ming Tseng^b, Li-Yao Chou^a, and Kuo-Chuan Ho^{a,c*}

^a Department of Chemical Engineering, National Taiwan University, Taipei 10617, Taiwan

^b Institute of Materials Science and Engineering, National Central University, Jhongli, Taoyuan 32001, Taiwan

^c Institute of Polymer Science and Engineering, National Taiwan University, Taipei 10617, Taiwan

S1. EIS spectra of the Co₃O₄ ANRAs and Co₃O₄ ANTAs electrodes

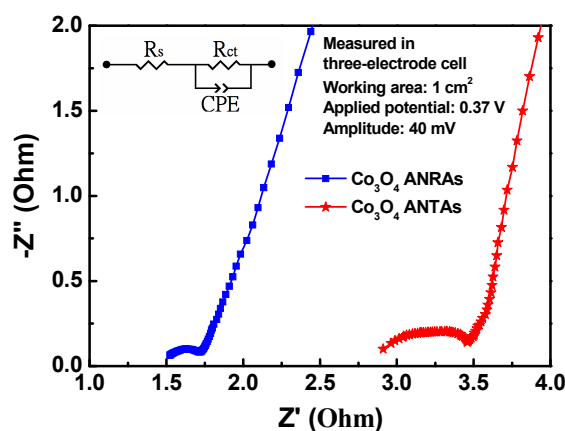


Figure S1. EIS spectra of the Co₃O₄ ANRAs and Co₃O₄ ANTAs electrodes, measured in 5.0 M KOH solution at 0.37 V vs. Ag/AgCl/KCl (sat'd) with an amplitude of 40 mV. *Inset:* the equivalent circuit, which is composed of the series resistance (R_s), charge-transfer resistance (R_{ct}), and constant phase element (CPE).

S2. Charge-discharge curves of the bare graphite, Co_3O_4 ANRAs and Co_3O_4 ANTAs electrodes at various charge-discharge current densities

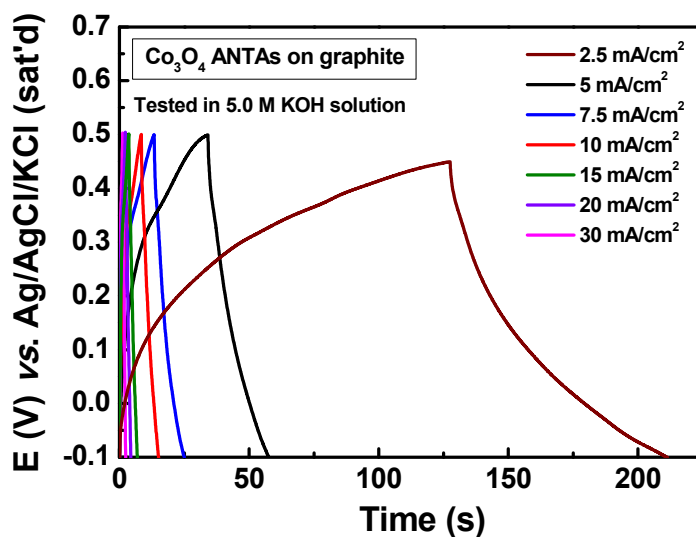


Figure S2. Charge-discharge curves of the Co_3O_4 ANTAs electrode measured in 5.0 M KOH solution at various charge-discharge current densities.

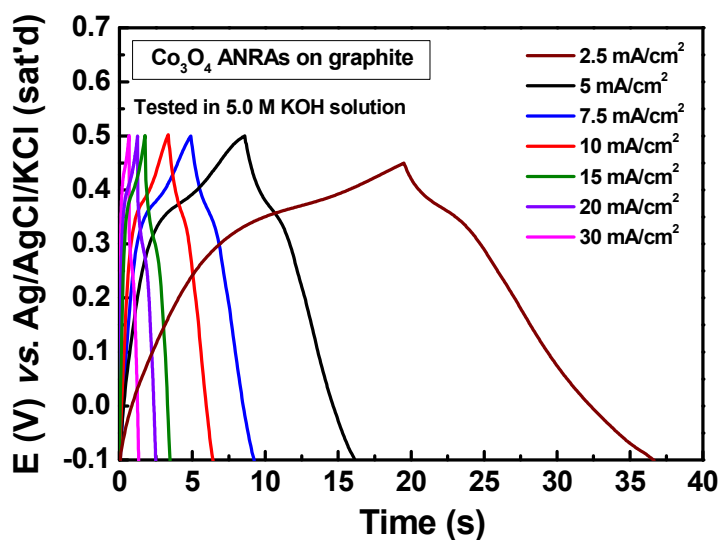


Figure S3. Charge-discharge curves of the Co_3O_4 ANRAs electrode measured in 5.0 M KOH solution at various charge-discharge current densities.

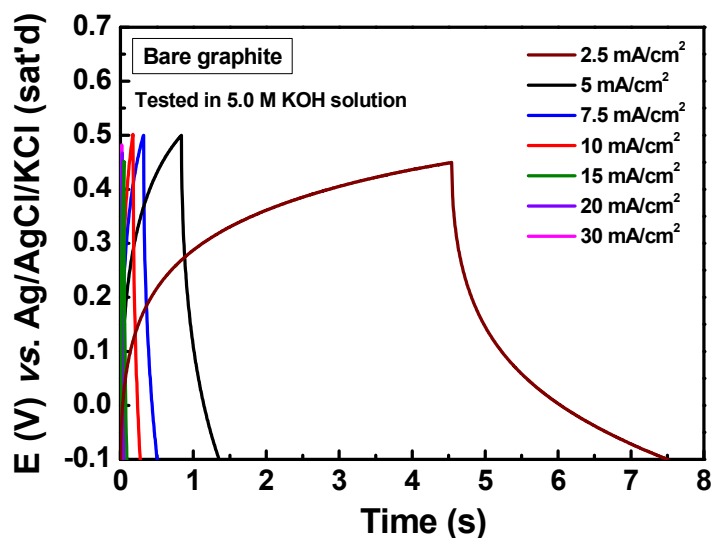


Figure S4. Charge-discharge curves of the bare graphite substrate measured in 5.0 M KOH solution at various charge-discharge current densities.

S3. Estimation of the film mass

The 37% HCl solutions containing various concentrations of CoCl_2 , with the color ranging from bright blue to transparent, were prepared. The UV-visible spectra of these solutions were measured, and their maximum absorbance at 663 nm was calibrated with the concentration of CoCl_2 , as shown in Fig. S5(a). Thereafter, the Co_3O_4 ANRAs and Co_3O_4 ANTAs thin films (3 cm^2 for each) were dissolved in two batches of 15 mL fresh 37% HCl solution, respectively. The UV-visible spectra of these two solutions were measured, as shown in Fig. S5(b). According to the absorbance at 663 nm shown in Fig. S5(b), the concentrations of Co^{2+} in the solutions of Co_3O_4 ANRAs and Co_3O_4 ANTAs are 0.84 mM and 0.94 mM, respectively. From the molecular weight of Co_3O_4 , the masses of the Co_3O_4 ANRAs and Co_3O_4 ANTAs thin films can be estimated

to be 0.34 mg/cm^2 and 0.38 mg/cm^2 , respectively.

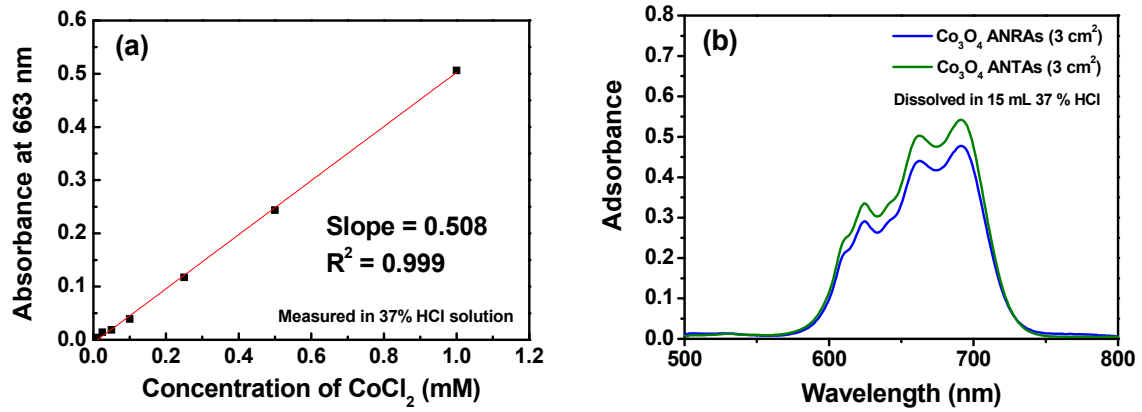


Figure S5. (a) Relationship between the absorbance of the CoCl_2 solution in 37% HCl at 663 nm and the concentration of CoCl_2 . (b) UV-visible spectra of the 37% HCl solutions after digesting the Co_3O_4 ANRAs and Co_3O_4 ANTAs thin films.

S4. Comparison to the reported studies using Co₃O₄ as pseudocapacitive material

Table S1. Partial list of recent reported studies using Co₃O₄ as pseudocapacitive material.

Morphology of Co ₃ O ₄	Substrate	High-temperature treatment to obtain Co ₃ O ₄	Specific capacitance (F/g)	Reference
Co ₃ O ₄ nanosheet arrays	Ni foam	✓	2,735	[S1]
Co ₃ O ₄ thin layer	Porous Ni substrate	✗	2,200	[S2]
Co ₃ O ₄ nanoflowers	Ni foam	✓	1,937	[S3]
Co ₃ O ₄ nanowires	Carbon fiber paper	✓	1,525	[S4]
Co ₃ O ₄ nanowire arrays	Ni foam	✓	1,257	[S5]
Co ₃ O ₄ nanowire arrays	Ni foam	✓	1,160	[S6]
Co ₃ O ₄ nanonet	Carbon fiber paper	✓	1,124	[S7]
Co ₃ O ₄ nanosheets	Ti foil	✗	1,033	[S8]
Co ₃ O ₄ acicular nanotube arrays	Graphite	✗	979	This work
Co ₃ O ₄ nanotubes	Ni foam	✓	574	[S9]
Co ₃ O ₄ microsphere arrays	RGO/CNT paper ^a	✗	378	[S10]
Co ₃ O ₄ nanoparticles	Ni foam	✓	363	[S11]
Co ₃ O ₄ hollow-sphere array	Ni foil	✓	358	[S12]
Hollow Co ₃ O ₄ boxes	Ni foam	✓	278	[S13]
Co ₃ O ₄ nanowires	Ni grid	✓	202	[S14]
Hollow Co ₃ O ₄ octahedra	Carbon fiber paper	✗	192	[S15]
Porous Co ₃ O ₄	Ni foam	✓	150	[S16]
Co ₃ O ₄ microtubules	Ni foam	✓	131	[S17]
Co ₃ O ₄ nanosheets	Ni grid	✓	92	[S18]

^a RGO/CNT = Reduced graphene oxide/carbon nanotubes

S5. Charge-discharge curves recorded during 2,000 cycles of measurement

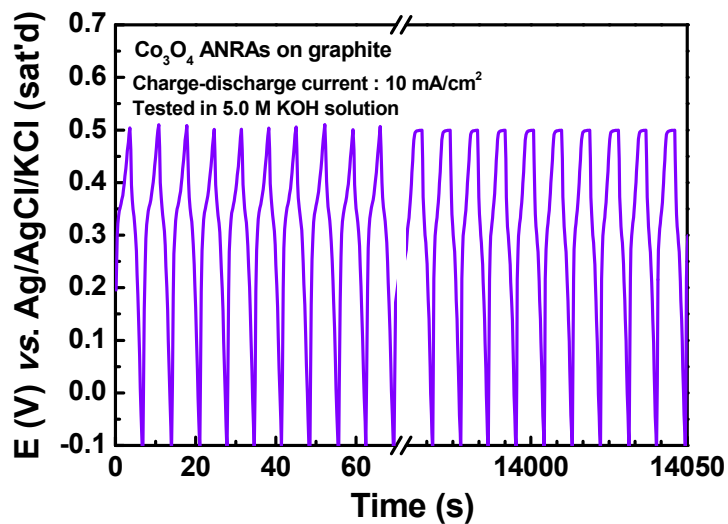


Figure S6. Charge-discharge curve of the Co₃O₄ ANRAs electrode measured in 5.0 M KOH solution at 10 mA/cm², recorded during 2,000 cycles of measurement.

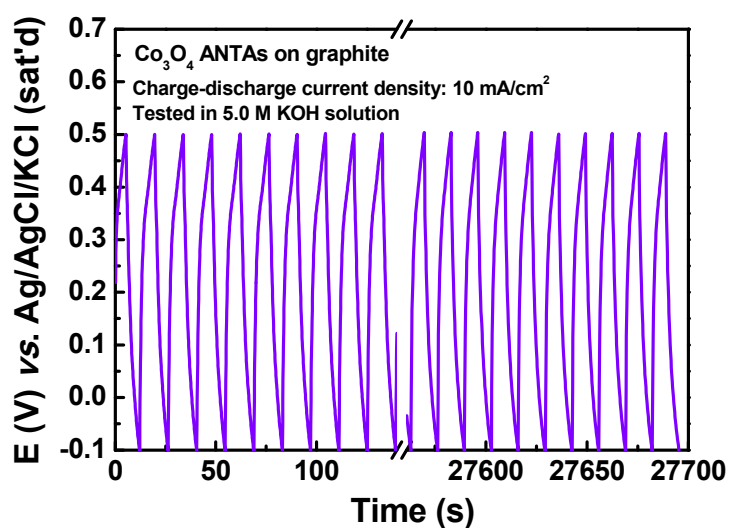


Figure S7. Charge-discharge curve of the Co₃O₄ ANTAs electrode measured in 5.0 M KOH solution at 10 mA/cm², recorded during 2,000 cycles of measurement.

S6. Morphologies of the films after 2,000 cycles of the charge-discharge process

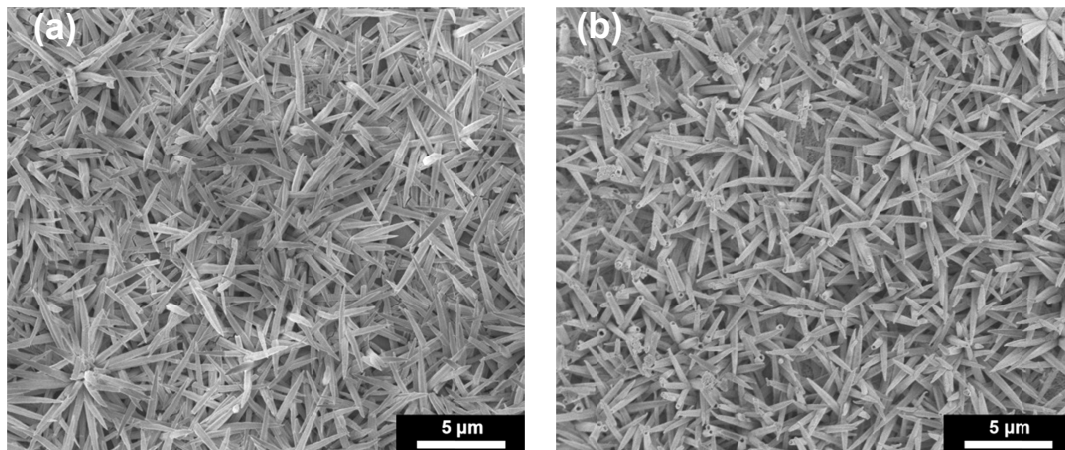


Figure S8. SEM images of the (a) Co_3O_4 ANRAs thin film, and (b) Co_3O_4 ANTAs thin film after 2,000 cycles of the charge-discharge process.

S7. Reference

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